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## Article:

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Layer	Material	Thickness	Dopant	Dopant	Doping
		(µm)		Туре	Density (cm <sup>-3</sup> )
1	GaAs	0.01	Be	$p^+$	$1 \times 10^{19}$
2	Al <sub>0.8</sub> Ga <sub>0.2</sub> As	0.5	Be	$\mathbf{p}^+$	$2 \times 10^{18}$
3	Al <sub>0.8</sub> Ga <sub>0.2</sub> As	1.7	Undoped		$< 10^{15}$
4	Al <sub>0.8</sub> Ga <sub>0.2</sub> As	1	Si	n <sup>+</sup>	$2 \times 10^{18}$
5	GaAs	0.25	Si	n <sup>+</sup>	$2 \times 10^{18}$
Substrate	n <sup>+</sup> GaAs				